Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/022,211	YOON, YEO-CHANG	
Examiner	Art Unit	
High V Ma	2062	

SEARCHED					
Class	Subclass	Date	Examiner		
702	39	4/7/03	WIL		
713	323		1		
	322				
	324				
315	8	·			
	364				
	368.1				
	370				
	371				
UPDAN	STA	Cett ABO	15		
		2/15/07	JXIF		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
702	89	3/7/07	WH		
315	8				
	368.21				
	371				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East	4/7/03	03
	02/15/07	uxlt
STIC SEARCH-(LitigAT	on Sand	
	2/1/07	Whi
Interfrence same		
4702/89	3/2407	VXII
315/8		
348/E3.04		
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